CIL

EMU CRITICAL ITEMS LIST

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| | | | | Date: 3/27/2002 |
|--|------|--|--|---|
| NAME P/N QTY | CRIT | FAILURE MODE & CAUSES | FAILURE EFFECT | RATIONALE FOR ACCEPTANCE |
| QTT | CKII | CAUSES | FAILURE EFFECI | RATIONALE FOR ACCEPTANCE |
| | | 156FM04 | | |
| REAL TIME DATA SYSTEM HARNESS, ITEM 156 | 2/2 | Electrical short or open in earphone lines. Cable chafing against connector shell or shield. Improper connector strain relief. Faulty connection between connector and the lead wires. | END ITEM: Open circuit or short to ground in earphone or microphone lines. | A. Design - Each connector/cable interface is strain relieved by potting the connectors in place with a rubber boot molded over and teflon coated. Wire is #24 AWG Teflon insulated and connectors are crimped per SVHS4909, Type II to provide electrical and mechanical properties to prevent breaking or shorting. Each connector/adapter ring interface is locked in place to prevent rotation by a mechanical lock and an adhesive lock. |
| | | | GFE INTERFACE: Loss of ability to receive radio signals. | B. Test - Component Acceptance Test - The 156 harness is subjected to acceptance testing per AT-EMU-156 prior to fina acceptance testing. This testing includes the following tests which insures there are no workmanship problems which would cause an electrical short to ground or an open circuit in the earphone lines. The insulation resistance and dielectric strength between each conductor and th shield ground is measured to insure there are no shorts. |
| | | | MISSION: Loss of one EMU. Terminate EVA. | Each connector/cable interface is pull tested (4.5 to 7.5 pounds depending on connector size) to detect any workmanship problems which could cause a prematur short circuit. Continuity testing of each conductor is performed after pull testing to insure there were no open circuits. |
| | | | CREW/VEHICLE: None. | PDA Test - The earphone lines are functionally checked during PLSS PDA testing per SEMU-60 010, Test 6.0, to insure there are no shorts to shield ground or opens which affect the performance of the earphones. |
| | | | TIME TO EFFECT /ACTIONS: Minutes. | Certification Testing - Certified for a useful life of 20 years (ref. EMUM1-0244). |
| | | | TIME AVAILABLE: N/A | C. Inspection - To insure there are no workmanship problems which would cause a short or open circuit in the harness conductors, the following inspections are performed: |
| | | | TIME REQUIRED: N/A | Harness cables and conductors are visually inspected prior to assembly to insur there are no defects which could cause a short to ground or an open circuit due to defects in the cable insulation. |
| | | | REDUNDANCY SCREENS: A-N/A B-N/A C-N/A | Connector wiring is inspected before and after potting to insure there is no conductor damage and that the conductors are properly strain relieved to preven conductor shorting to the adapter ring or an open circuit. |
| | | | | Insulation resistance and dielectric strength are measured between each conductor and shield ground to insure there are no shorts prior to and after potting of the connectors. Contact crimp samples are made prior to the start of contact crimping and at the conclusion of crimping and subjected to a pull test to insure the crimping tools are operating properly. This insures there will not be any high resistance problems at the conductor. |
| | | | | D. Failure History - H-EMU-156-A001 (6/22/89) Low insulation resistance between earphone signal high conductor and grounded shield circuit. Disassembly of wire harness at J10A connector revealed earphon |
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| | | 156FM04 | | | |
| | | | | high wire insulation damage which exposed wire. Cau force to pull the wire through the EMI shield. Second tubing) at breakout point missing due to improperly RTDS harness manufacturing process modified to spect needed for proper shrink tubing installation and vis wire breakout and shrink tubing assembly operations | ondary insulation (shrink positioned shrink tubing. ify amount of exposed shiel sual inspection points for |
| | | | | B-EMU-156-A002 (2/29/00) - P10B connector outer hous inspection of RTDS harness, such that it could resul Service instructions for incorporation of bowed was inadequate, resulting in confusion of harness config with grounding fingers to have bowed washers instal 439 Rev. B screens 152, 153, and 156 harnesses. SI- 153, and 156 configurations per EC 42807-129-2. | lt in a loose connection. her (-2) configuration were gurations allowing harnesse led. Service Instruction SI |
| | | | | E. Ground Turnaround - Tested for non-EET processing per FEMU-R-001, Final FEMU-R-001 Para 8.2 EMU Preflight KSC Checkout for H | |
| | | | | F. Operational Use - Crew Response - PreEVA: Trouble shoot problem. If no success, considered otherwise terminate EVA prep. EVA: When loss of minimum comm occurs, terminate EVA Training - Standard training covers this failure mode. Operational Considerations - EVA checklist procedures verify hardware integrity a prior to eVA. Flight rules require that EVA be terminate communication between each EV crewmember and orbited relay, is unavailable. | A. and system operational stat inated if two-way |

EXTRAVEHICULAR MOBILITY UNIT

SYSTEMS SAFETY REVIEW PANEL REVIEW

FOR THE

I-156 REAL TIME DATA SYSTEM HARNESS

CRITICAL ITEM LIST (CIL)

EMU CONTRACT NO. NAS 9-97150

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